

RF Exposure Report

Report No.: SA170629C07

FCC ID: K7SF2CU053

Test Model: F2CU053

Received Date: Jun. 29, 2017

Test Date: Jul. 04, 2017

Issued Date: Jul. 05, 2017

Applicant: Belkin Electronics (Changzhou) Co.,Ltd.

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Hi-Tech Industrial Zone, Changzhou City, Jiangsu, China

Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch

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R.O.C.

Test Location: No. 19, Hwa Ya 2nd Rd., Wen Hwa Vil., Kwei Shan Dist., Taoyuan City

33383, TAIWAN (R.O.C.)

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Release Control Record

Issue No.	Description	Date Issued
SA170629C07	Original release	Jul. 05, 2017



1 Certificate of Conformity

Product: 4 feet Apple watch charging cable

Brand: belkin

Test Model: F2CU053

Sample Status: Engineering sample

Applicant: Belkin Electronics (Changzhou) Co.,Ltd.

Test Date: Jul. 04, 2017

Standards: FCC Part 1 (Section 1.1307(b), 1.1310)

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by: ______ Chou___, Date: _____ Jul. 05, 2017

Celine Chou / Specialist

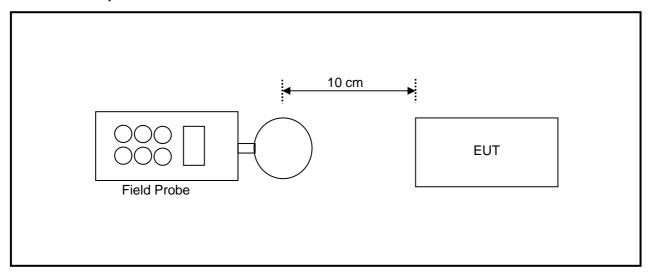
Approved by: ______, Date: Jul. 05, 2017

Ken Liu / Senior Manager



2 RF Exposure

2.1 Test Setup



Note: Measurements should be made from all sides and the top of the primary/client pair, with the 10 cm measured from the center of the probe(s) to the edge of the device.

2.2 Test Instruments

Description	Brand	Model No.	Frequency Range	Calibrated Date	Calibrated Until
Broadband Field Meter	NARDA	NBM-550	-	Feb. 9, 2016	Feb. 8, 2018
Magnetic Field Meter	NARDA	ELT-400	1 – 400kHz	Feb. 11, 2016	Feb. 10, 2018
Magnetic Probe	NARDA	HF-3061	300kHz – 30MHz	Feb. 9, 2016	Feb. 8, 2018
Magnetic Probe	NARDA	HF-0191	27 – 1000MHz	Feb. 9, 2016	Feb. 8, 2018
Broadband Field Meter	NARDA	NBM-550	-	Feb. 9, 2016	Feb. 8, 2018
Electric Field Meter	COMBINOVA	EFM 200	5Hz – 400kHz	Oct. 16, 2016	Oct. 15, 2017
E-Field Probe	NARDA	EF-0391	100kHz – 3GHz	Feb. 9, 2016	Feb. 8, 2018
E-Field Probe	NARDA	EF-6091	100MHz – 60GHz	Feb. 9, 2016	Feb. 8, 2018

Note: 1. The calibration interval of the above test instruments is 12/24 months and the calibrations are traceable to NML/ROC and NIST/USA.

2. The test was performed in HwaYa RF Chamber



2.3 **Limits for Maximum Permissible Exposure (MPE)**

§ 1.1310 The criteria listed in table 1 shall be used to evaluate the environmental impact of human exposure to radiofrequency(RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

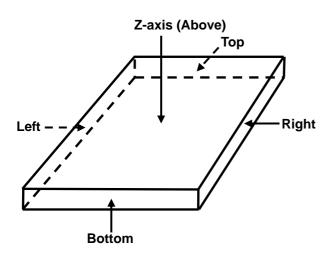
Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)
(A) Lim	its for Occupational	/Controlled Exposur	es	
0.3–3.0	614	1.63	*(100)	6
3.0-30	1842/f	4.89/f	*(900/f2)	6
30-300	61.4	0.163	1.0	6
300-1500			f/300	6
1500-100,000			5	6
(B) Limits	for General Populati	on/Uncontrolled Exp	oosure	
0.3–1.34	614	1.63	*(100)	30
1.34-30	824/f	2.19/f	*(180/f ²)	30
30–300	27.5	0.073	0.2	30
300-1500			f/1500	30
1500-100,000			1.0	30

f = frequency in MHz

680106 D01 RF Exposure Wireless Charging Apps v02

Aggregate leakage fields at 10 cm surrounding the device from all simultaneous transmitting coils are demonstrated to be less than 30% of the MPE limit.

2.4 **Test Point Description**



<sup>T = frequency in MHZ

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.</sup>



3 Calculation Result Of Maximum Conducted Power

Charging mode

E-Field Measurement (10cm)							
EUT Side	Left	Right	Тор	Bottom	Z-axis (Above)		
Max E-field (V/m)	0.47	0.44	0.53	0.65	0.56		
Limit (V/m)	614	614	614	614	614		
Margin (V/m)	-613.53	-613.56	-613.47	-613.35	-613.44		
70 % Limit (V/m)	429.8	429.8	429.8	429.8	429.8		
70 % Margin (V/m)	-429.471	-429.492	-429.429	-429.345	-429.408		

H-Field Measurement (10cm)							
EUT Side	Left	Right	Тор	Bottom	Z-axis (Above)		
Max H-field (uT)	0.242	0.248	0.247	0.244	0.246		
Max H-field (A/m)	0.1936	0.1984	0.1976	0.1952	0.1968		
Limit (A/m)	1.63	1.63	1.63	1.63	1.63		
Margin (A/m)	-1.4364	-1.4316	-1.4324	-1.4348	-1.4332		
70 % Limit (A/m)	1.141	1.141	1.141	1.141	1.141		
70 % Margin (A/m)	-1.00548	-1.00212	-1.00268	-1.00436	-1.00324		



Standby mode

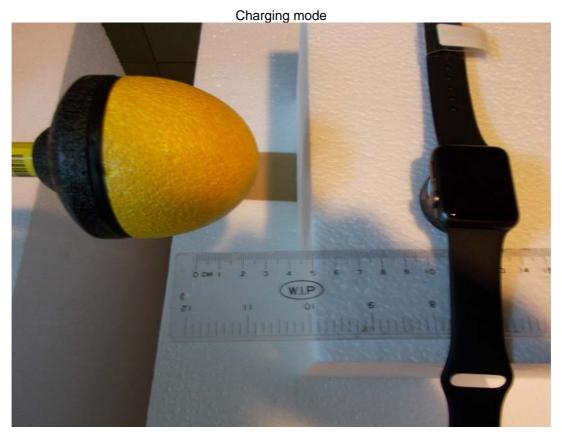
E-Field Measurement (10cm)							
EUT Side	Left	Right	Тор	Bottom	Z-axis (Above)		
Max E-field (V/m)	0.29	0.32	0.43	0.56	0.48		
Limit (V/m)	614	614	614	614	614		
Margin (V/m)	-613.71	-613.68	-613.57	-613.44	-613.52		
70 % Limit (V/m)	429.8	429.8	429.8	429.8	429.8		
70 % Margin (V/m)	-429.597	-429.576	-429.499	-429.408	-429.464		

H-Field Measurement (10cm)							
EUT Side	Left	Right	Тор	Bottom	Z-axis (Above)		
Max H-field (uT)	0.242	0.242	0.243	0.244	0.241		
Max H-field (A/m)	0.1936	0.1936	0.1944	0.1952	0.1928		
Limit (A/m)	1.63	1.63	1.63	1.63	1.63		
Margin (A/m)	-1.4364	-1.4364	-1.4356	-1.4348	-1.4372		
70 % Limit (A/m)	1.141	1.141	1.141	1.141	1.141		
70 % Margin (A/m)	-1.00548	-1.00548	-1.00492	-1.00436	-1.00604		

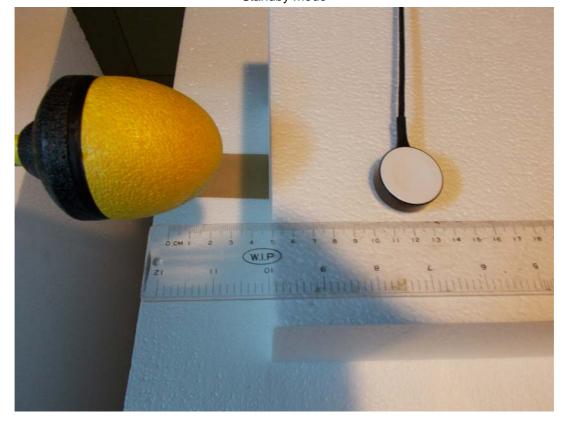
Measurements was made from all sides and the top of the primary/client pair, with the 10 cm measured from the center of the probe(s) to the edge of the device. The highest emission level was recorded.



4 Photographs of the Test Configuration



Standby mode



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